



SHEET 1 OF 1

INFORMATION DISCLOSURE
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Nobuyuki OTSUKA, et al.FILING DATE
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EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
SWC		HANG, D.R. et al., "Shubnikov-de Haas oscillations of two-dimensional electron gas in and in AsN/InGaAs single quantum well", <i>Semiconductor Science and Technology</i> , Vol. 17, no. 9, September 2002, pp. 999-1003
SWC		WANG, Jyh-Shyang et al., "Growth of InAsn/InGaAs (P) quantum wells on InP by gas source molecular beam epitaxy", <i>Journal of Vacuum Science & Technology B</i> , Vol. 19, No. 1 January/February 2001, pp 202-206

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